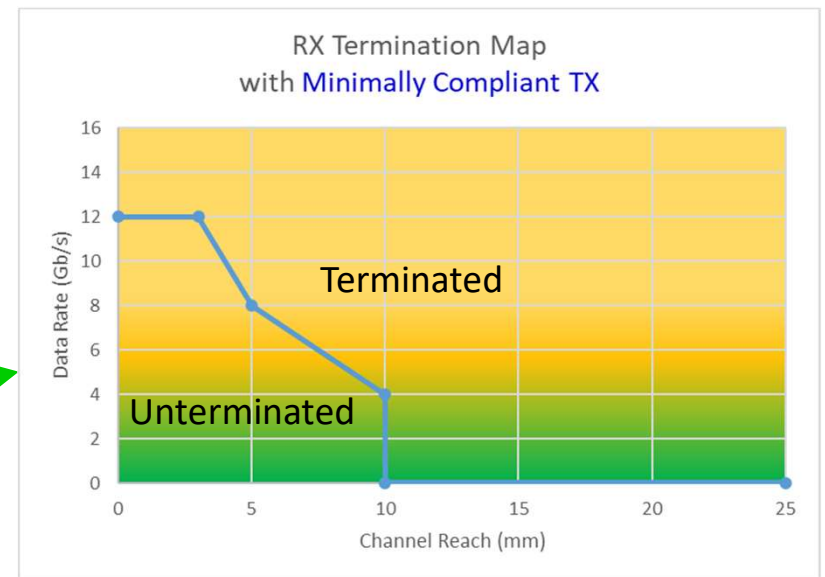


Electrical, Form-Factor, and Compliance

Data Rate, BER, and Channel Reach

- Signaling: Unidirectional NRZ
- Data Rate: 4, 8, 12, 16, 24, 32 Gb/s.
- Channel Reach:
 - Advanced Package (25-55um bump pitch):
 - Up to 2mm and 32Gb/s, TX drive control.
 - No RX Termination
 - Standard Package (100-130um bump pitch):
 - TX Termination
 - RX Termination Map
- BER:

Data Rate (Gb/s)	4	8	12	16	24	32
Advanced Package	1.00E-27	1.00E-27	1.00E-27	1.00E-15	1.00E-15	1.00E-15
Standard Package	1.00E-27	1.00E-27	1.00E-15	1.00E-15	1.00E-15	1.00E-15

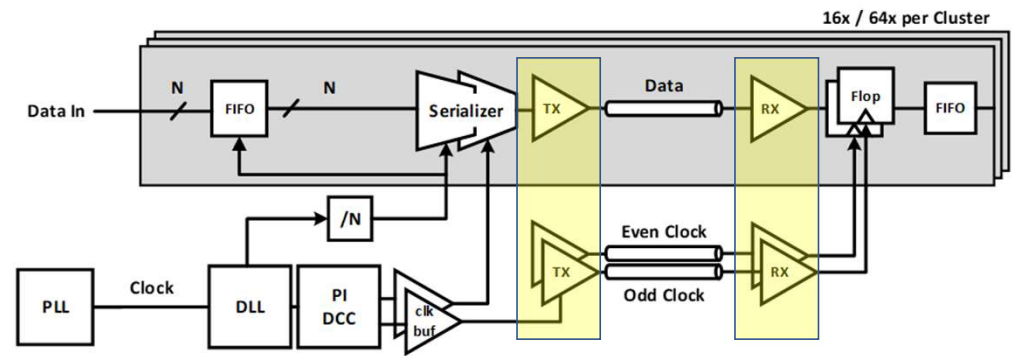
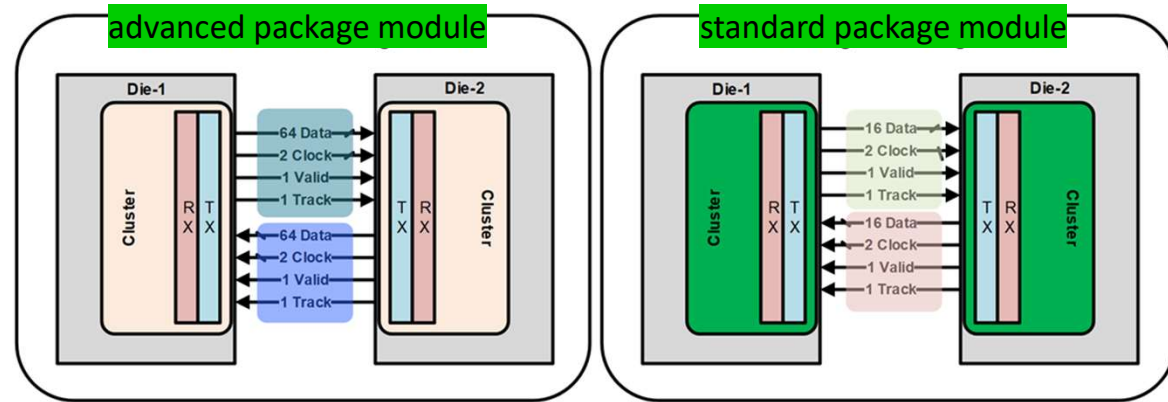


Reach for unterminated RX can be increased with higher swing TX

CRC and Retry for BER 1E-15 to achieve FIT rate <<1

PHY Architecture

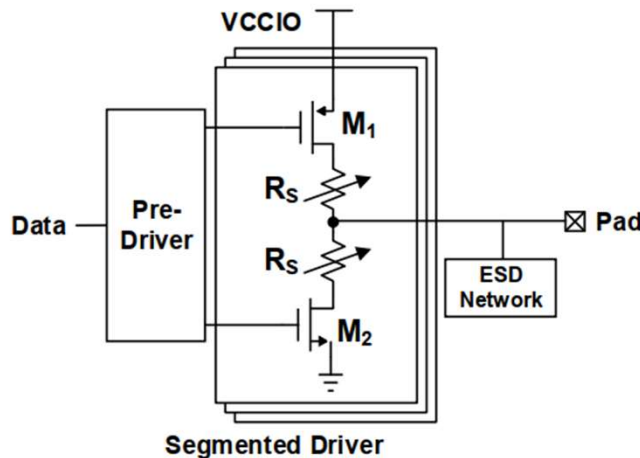
- Basic module data width:
 - x64 for advanced packaging
 - x16 for standard packaging
- Differential Forwarded Clock, Single-Ended Data.
- “Matched” Architecture
 - Better tolerance to power supply noise
- Matched Interconnect Channels
 - Significant power reduction in clock recovery
- SSC allowed, 0 ppm TX to RX



Driver and Input Buffer

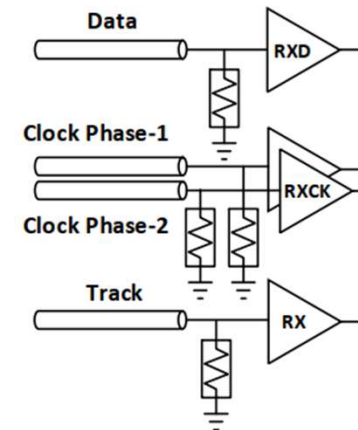
TX Driver

- Typical segmented driver
- CMOS implementation shown. NN driver and other structure possible.
- Target source impedance based on optimal eye open, not necessary matching T-Line impedance.
- BW and rise/fall time defined by R_{term} and C_{pad} spec
- **TXLE** (1-tap de-emphasis) required at 24G+
 - Trained at link-initialization, no realtime adaptation



RX Input Buffer

- Termination (when applicable) is to ground, and matching T-Line impedance.
- Spec does not mandate a specific input buffer design. If RX amplifier is used, recommend BW of $> 0.75 \times$ data rate ($1.5 \times$ Nyquist).
- Optional RX CTLE



TX and RX Voltage Compatibility

- Minimum TX swing 0.4V
- Strongly recommend max TX voltage < 0.85V for compatibility with future process nodes

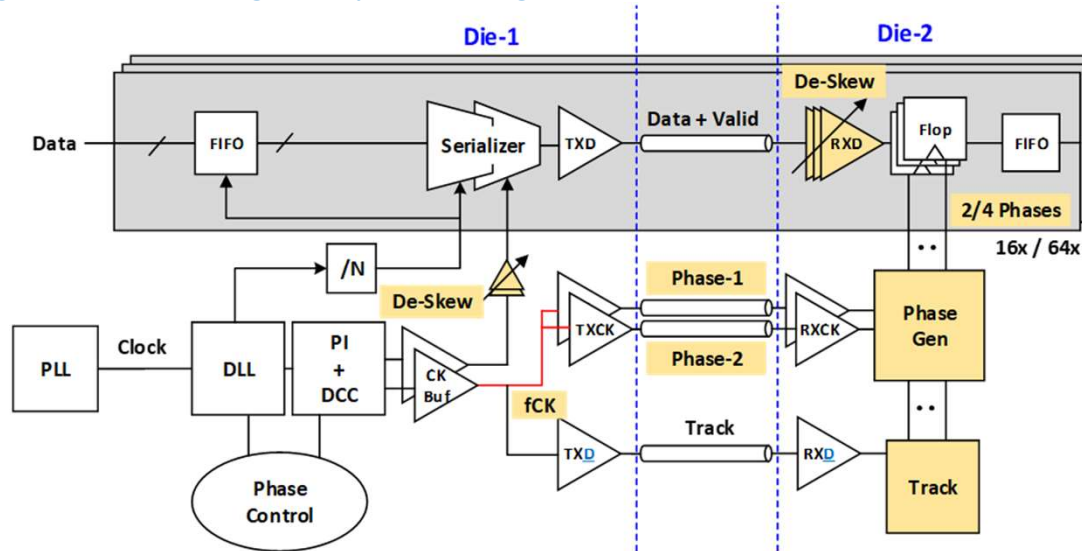
Transmitter V_{OH} and Receiver VCC compatibility guidelines				
Die 1 TX output maximum V_{OH} (V)	V_{OH}	V_{OH}	V_{OH}	V_{OH}
Die 2 RX AFE VCC level (V)	$V_{OH} - VCC < 0mV$	$V_{OH} - VCC = 0mV$	$V_{OH} - VCC < 100mV$	$V_{OH} - VCC > 100mV$
Compatibility	Safe	Safe	Safe	Not Safe*

- Cross Process Reliability and Electrical Overstress (EOS) concerns
 - To avoid reliability issues (voltage overstress above allowable process limits: EOS), recommend limiting the TX output high (V_{OH}) to a maximum of 100mV above the RX supply rail.
 - When the TX V_{OH} is equal to or lower than the RX AFE supply rail, within ranges in the spec, there won't be reliability concerns.
- In the case of "Not Safe*", RX AFE overstress protection circuitry can be used to mitigate the issue, at cost of area and power consumption.

PHY Clocking Architecture

- Supports 2-way and 4-way interleaving TRX
- Independent even/odd phase control
- Global TX, local TX, local RX phase adjustments depending on data rate.
- Data Valid bit to gate clock distribution (also for data framing)
- Track bit for background training and phase alignment

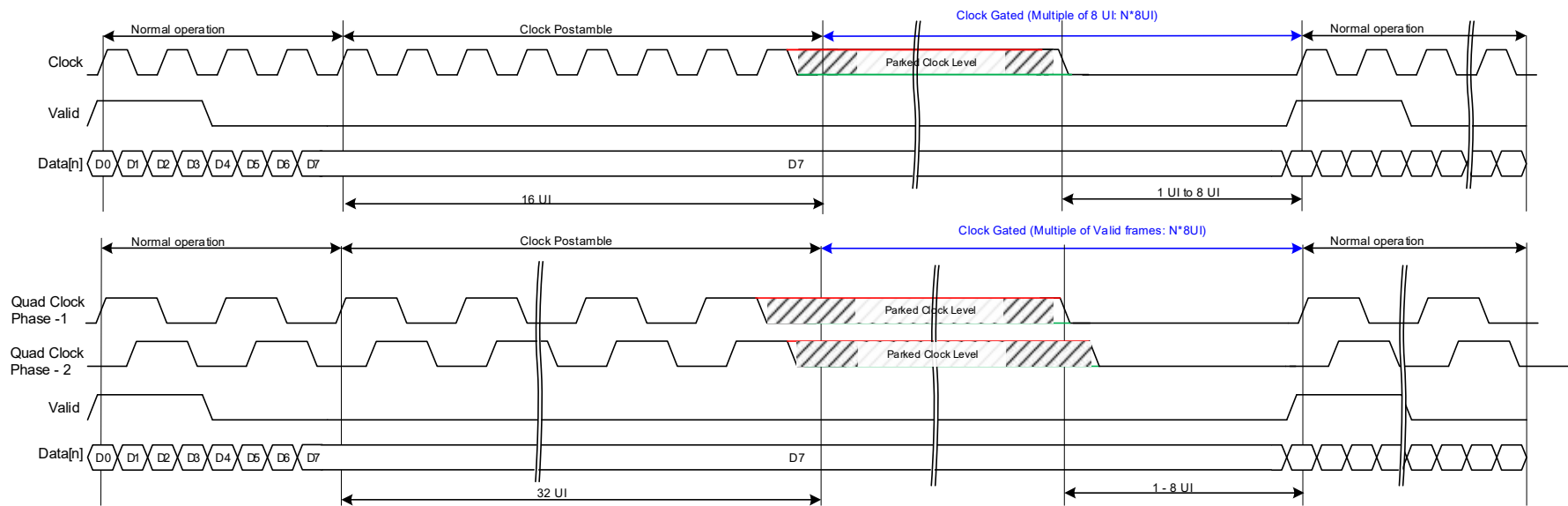
Data rate (GT/s)	Clock freq. (fCK) (GHz)	Phase -1	Phase -2	De-skew (Req/Opt)
32	16	90	270	Required
	8	45	135	Required
24	12	90	270	Required
	6	45	135	Required
16	8	90	270	Required
12	6	90	270	Required
8	4	90	270	Optional
4	2	90	270	Optional



Dynamic Clock Gating

- Clock gated if Valid remains low after providing postamble
 - No clock gating if free running clock mode is negotiated
- Clock parked Hi/Low during alternate clock gating events; 8 UI boundary

UCIE Dynamic Clock Gating (unterminated link example)

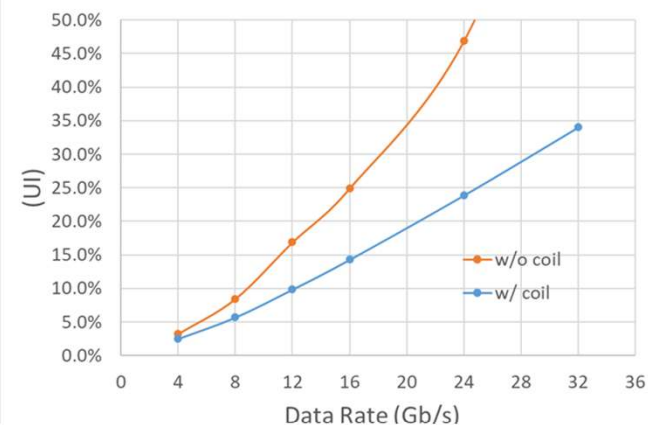


Pad Capacitance and ESD

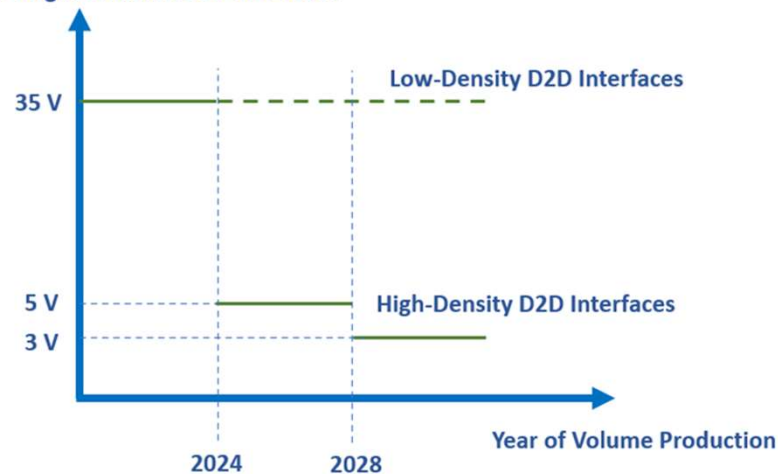
- Cpad has 1st order performance impact
- Aggressive targets on Cpad and ESD
- UCle 1.0 ESD spec: **30V CDM**, further scaling in future, align with Industry Council on ESD Targets.
- **T-coil** to reduce effective pad capacitance
 - T-coil widely used by serial I/O across industry
 - T-coil size expected to be on the order of 20um x 20um x2

TX/RX Pad Capacitance	250/200 fF	Advanced Package Mode
TX/RX Pad Capacitance (8Gb/s capable design)	300 fF	Standard Package Mode
TX/RX Pad Capacitance (16Gb/s capable design)	200 fF	Standard Package Mode Effective Cpad
TX/RX Pad Capacitance (32Gb/s capable design)	125 fF	Standard Package Mode Effective Cpad

T-coil impact to standard package channel



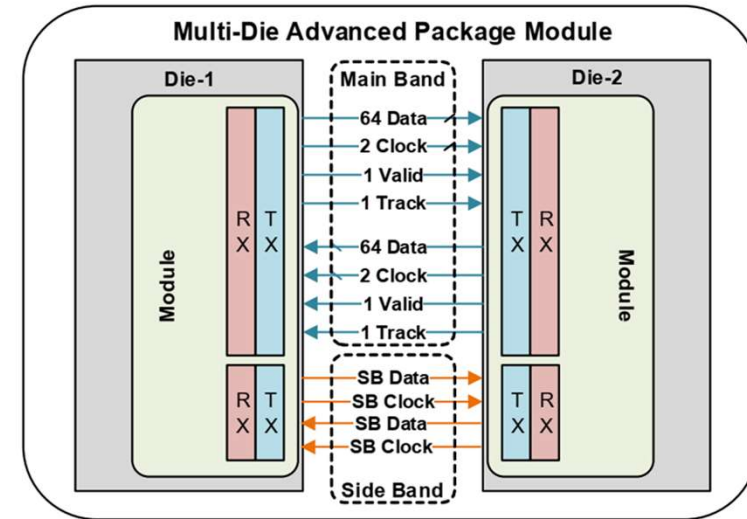
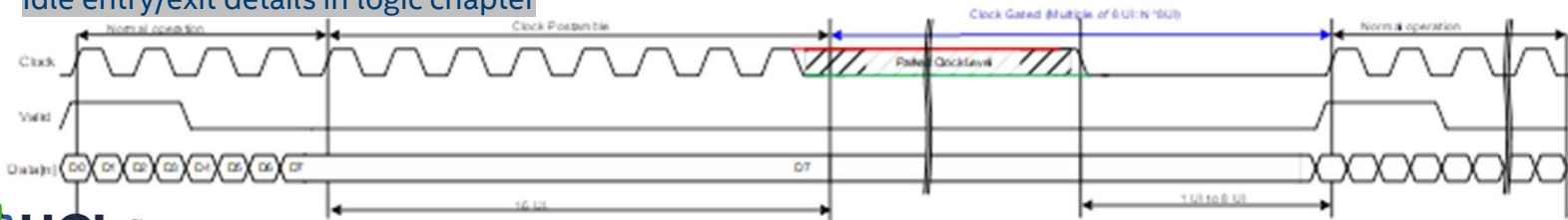
CDM Target Level for D2D Interfaces



Other PHY Features

- 800MT/s 2-wire sideband per module
- Global signals (DFX etc.)
- Low Datapath Latency: 12 UI up to 16Gb/s, 16 UI 24-32Gb/s.
- Ultra Fast Idle Exit:
 - L0-idle Power State through Data Valid Clock gating
- L1 power state (options for further power down)
- Redundancy & Repair for Advanced Package
 - Two per 32 bits
- **Data Scrambling** to mitigate power supply noise

Idle entry/exit details in logic chapter



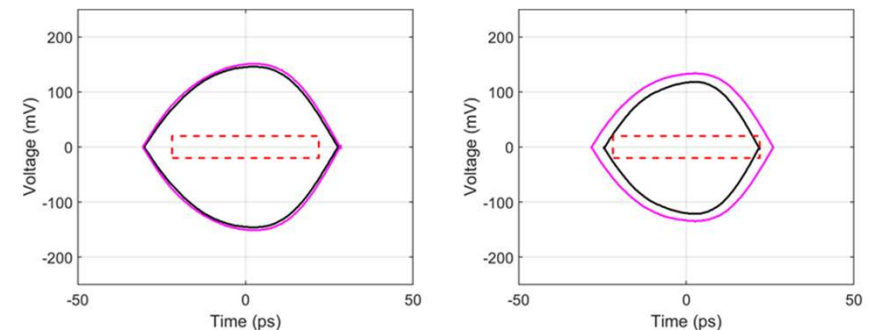
Sideband used for training, debug, management...
 Figure is logical illustration
 Physically sideband leverages depopulated bumps
 No impact to shoreline / die edge BW density

Channel Specification

- Channel needs to meet minimum eye mask under channel compliance simulation with noiseless jitter-less behavioral TX and RX models

Data Rate	4-16Gb/s	24-32Gb/s
Overall (Eye Closure due to Channel)		
Eye Height	40mV	40mV
Eye Width (rectangular eye mask with specified eye height)	0.75 UI	0.65 UI with Equalization Enabled

Pass/fail eye mask example

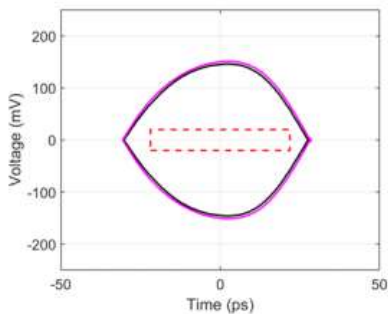


Insertion loss and Crosstalk spec defined based on the criteria using Voltage Transfer Function (VTF) method

- Due to short transmission line, VTF is more practical than S-parameter based method.

Tightly Coupled Mode

- Both Conditions must be met:
 - Shared Power Supply or Forwarded Power Supply
 - Channel supports larger eye mask
- Rationale / Advantages:
 - Further Optimization of PHY Circuits to lower power. For example, inverter-based RX, no front amplifier.
 - Reduced Training Complexity, such RX reference voltage training.
 - Preparation for higher density D2D



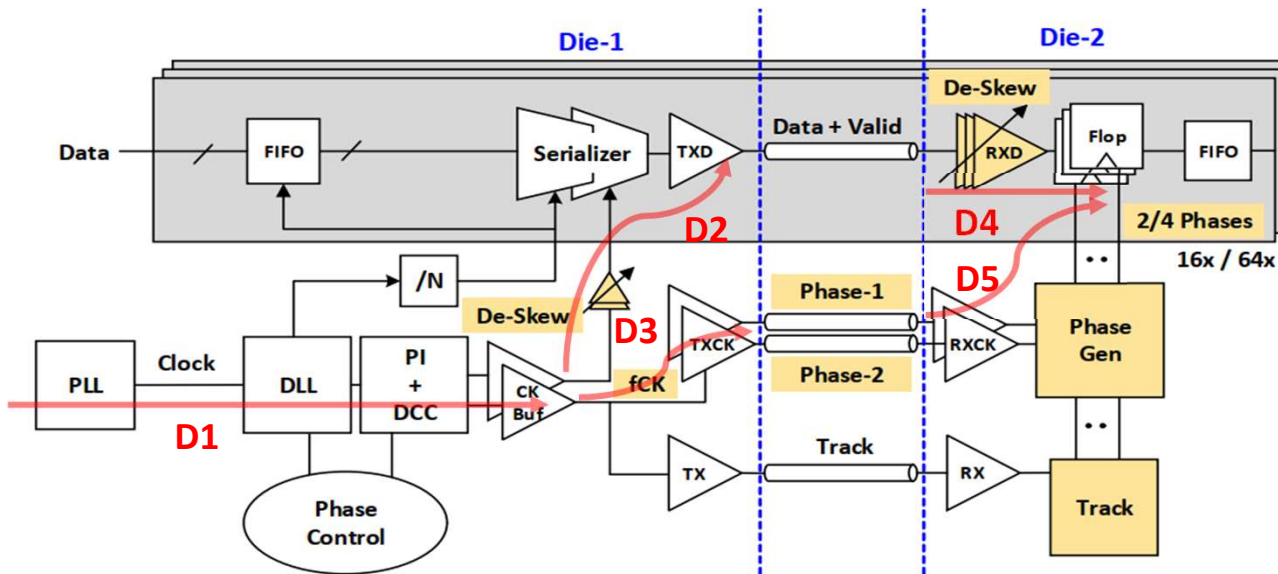
Data Rate	4-16Gb/s	24-32Gb/s
Overall (Eye Closure due to Channel)		
Eye Height	40mV	40mV
Eye Width (rectangular eye mask with specified eye height)	0.75 UI	0.65 UI with Equalization Enabled



Eye mask for channel changes to
250mV / 0.7UI for TX swing 0.75V
Up to 16Gb/s

TX and RX Jitters

Specify 1-UI TX jitter, data/clock differential TX jitter, and data/clock differential RX jitter.



- D1: Tx Common clock delay
- D2: Tx Data path clock delay
- D3: Tx FWD clock path delay
- D4: Rx Data path delay
- D5: Rx Clock path delay

$E(D3) = E(D2) + nT$, E is the mean, $n = 0.5$ for matched arch
 Jitter = $D1(t-nT) - D1(t) + D3(t-nT) - D2(t) - nT + D5(t) - D4(t)$

→ Jitter = $D(t-nT) - D(t) + \delta D_T(t) - nT + \delta D_R(t)$

where $D = D1 + D3$ (total delay), $\delta D_T = D3 - D2$, $\delta D_R(t) = D5 - D4$

Link Timing Analysis

Timing parameters

	Name	Note
Eye Closure due to Channel	Ch	from SI analysis
Channel Mismatch	Chm	
n-UI TX Total Jitter	Tjnui	specified at BER
TX Data/Clock Differential Jitter	Tjtx	specified at BER
TX Duty Cycle Error	Dce	post correction
TX Lane-to-lane Skew Correction Range	Rstx	
TX Lane-to-Lane Skew	Stx	post correction
Clock to Mean Data Training Accuracy	Eckd	including static and tracking error
RX Data/Clock Differential Jitter	Tjrx	specified at BER
Max RX Lane-to-Lane Skew	Msrx	if exceeding limit, requires RX lane-to-lane deskew
RX Phase Error	Eph	including duty cycle and I/Q mismatch
Sampling Aperture	Ap	

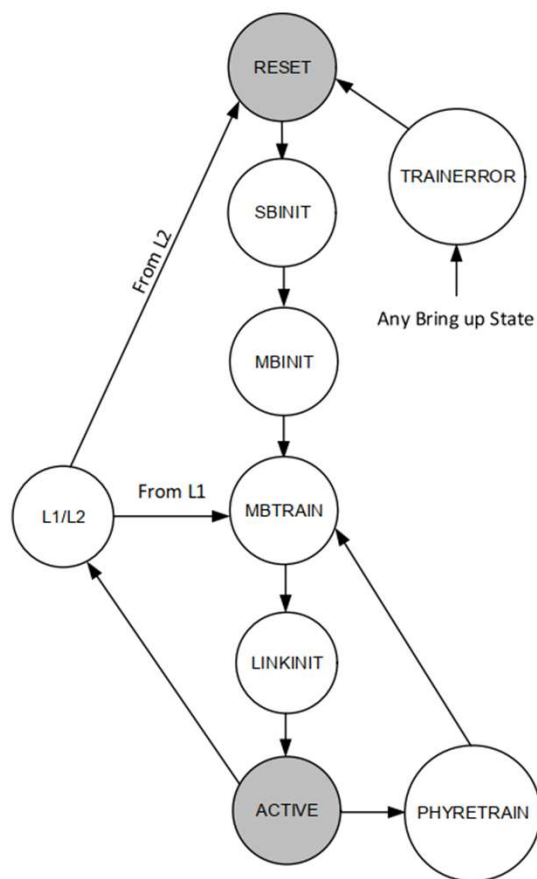
- Need to meet the following conditions (range defined as peak-to-peak)

$$C_h + T_{jnui} + D_{ce} + S_{tx} + E_{ckd} + T_{jrx} + E_{ph} + A_p \leq 1UI$$

$$C_{hm} \leq R_{stx} - M_{srx}$$

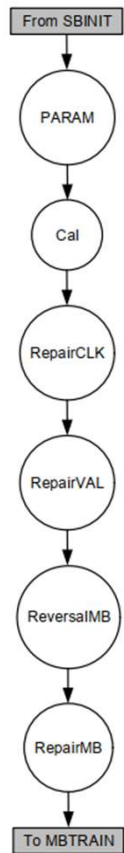
- Detailed numbers at different data rates are in the spec and WG discussions

Link Training and Status State Machine



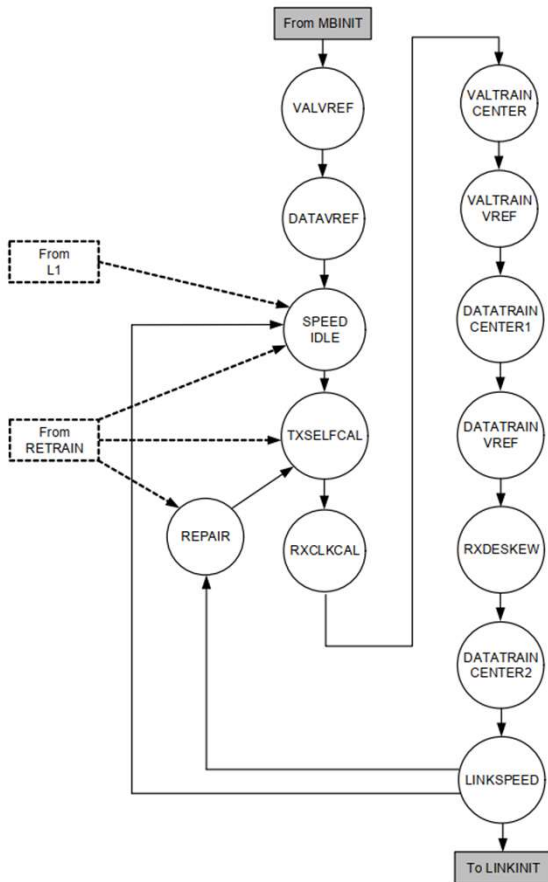
- Sideband (SB) initialization
 - Initialization and repair (advanced interface) of SB
- Main band (MB) initialization
 - Parameter exchange, CLK, Valid & MB repair & MB reversal
- Main band training
 - Data training, at speed repair/degrade and speed degrade
- Link init
 - Exchange RDI Link management messages
- PHYRETRAIN: Retrain based on Link errors
 - Allow infield repair and degrade
- L1/L2: Lower power state
- Train error: For uncorrectable internal errors and Link down conditions //state timeouts and SB timeouts
- Active: Transactions are sent and received

Main band Initialization



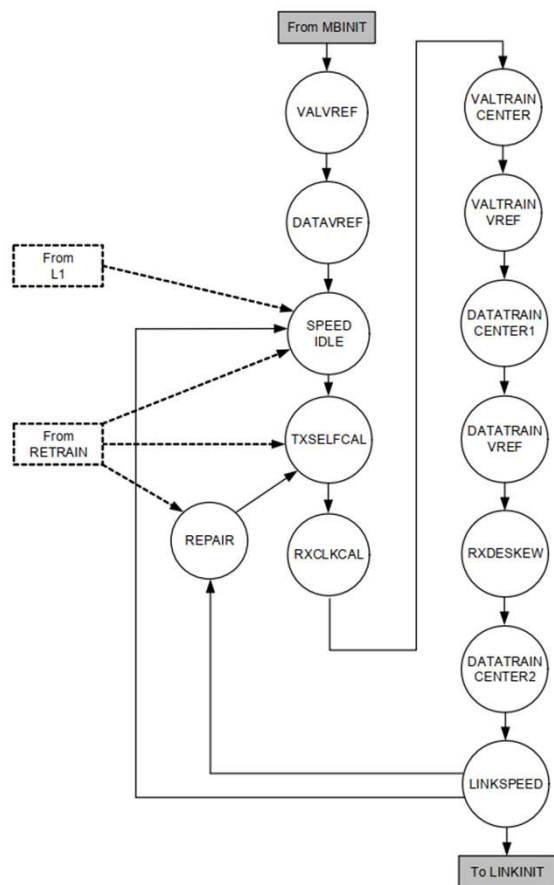
- Data rate set to 4GT/s for main band
- Param
 - Exchange of parameters required to setup maximum speed and other PHY settings
- Cal
 - Perform any required calibration (ex: Tx Duty Cycle, Rx Vref etc.)
- RepairCLK
 - Detect and apply repair (if needed) to clock and track Lanes for Advanced Pkg
 - Functional check of clock and track Lanes for Standard Pkg
- RepairVAL
 - Detect and apply repair (if needed) to Valid Lane for Advanced Pkg
 - Functional check of Valid for Standard Package interface.
- ReversalMB
 - Detect and apply Lane reversal (both Standard and Advanced package)
- RepairMB
 - Detect and apply repair (if needed) for Advanced Pkg interface
 - Functional check and width degrade (if needed) for Standard Pkg interface.

Main band Training



- VALVREF
 - Receiver reference voltage (Vref) to sample the incoming Valid
 - Performed through Rx initiated point tests or sweep using Valtrain pattern
- DataVref
 - Receiver reference voltage (Vref) to sample the incoming Data
 - Performed through Rx initiated point tests or sweep using LFSR pattern
- Speed Idle
 - Frequency changed to highest negotiated Data rate
- TxSelfCal
 - UCie Module calibrates its circuit parameters independent of the UCie Module Partner
- RxClkCal
 - Perform calibration on Clock receive path and align Clock/Track alignment
- ValTrainCenter
 - Valid to clock centering and ensure Valid functionality

Main band Training [2]



- ValTrainVref
 - Optional operation within the state to allow at speed Vref training on Valid signal
- DataCenter1
 - Full Data to clock training with correct Valid framing
 - Tx initiated point tests or eye width sweep with LFSR pattern
- DataTrainVref
 - Optional operation within the state to allow at speed Vref training on Data
- RxDeSkew
 - Optional Operation within the state to allow Lane-to-Lane skew correction on Rx if needed
- DataCenter2
 - Recentering if Rx performs Deskew
- LinkSpeed
 - Link stability check; direct Link to repair or speed degrade if needed
- Repair
 - Apply repair for Advanced pkg and Width degrade for Standard pkg

Electrical Summary

	Standard Package	Standard Package	Standard Package	Standard Package	Advanced Package	Advanced Package	Advanced Package
Data Width	16	16	16	16	64	64	64
Data Rate (Gb/s)	4-16	4/8/12	16	24/32	4/8/12	16	24/32
Power Efficiency Target (pJ/b)	0.25-0.5	0.5-1	0.5-1	0.75-1.25	0.25-0.5	0.3-0.6	0.3-0.6
Latency Target (TX+RX) (UI)	12	12	12	16	12	12	16
Idle Power (% of peak)	15%	15%	15%	15%	15%	15%	15%
Channel Reach (mm)	2-10	25	25	25	2	2	2
Die Edge BW Density (GByte/s/mm)	28-112	28-84	112	168/224	165-494	658	988/1317
BW Area Density (GByte/s/mm ²)	21-85	21/42/64	85	109/145	158/316/473	631	710/947
PHY dimension Width (um)	571.5	571.5	571.5	571.5	388.8	388.8	388.8
PHY dimension Depth (um)	1320	1320	1320	1540	1043	1043	
ESD	30V CDM (Further scaling in future, align with Industry Council on ESD Targets)						

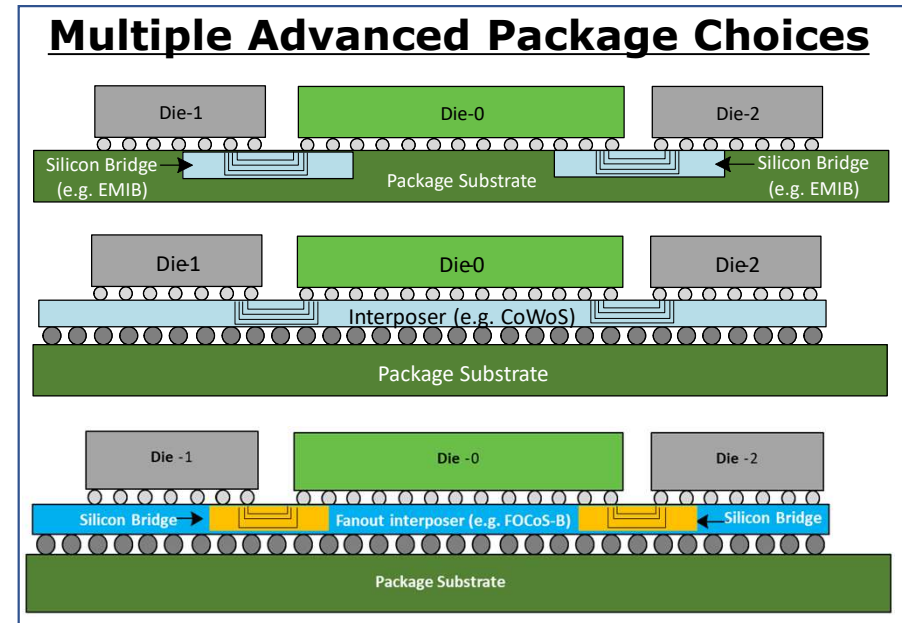
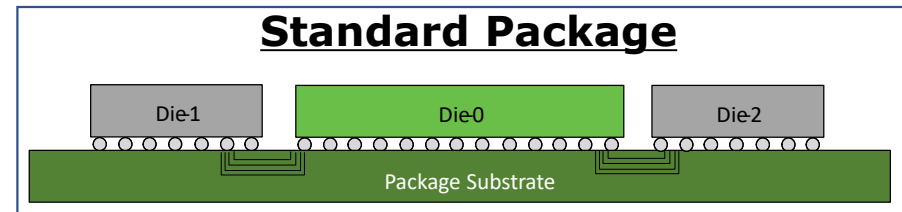
Advanced package PHY depth depends on bump pitch, number based on 45um

Coffee Break



UCIe 1.0: Supports Standard and Advanced Packages

- Standard Package: 2D – cost effective, longer distance
- Advanced Package: 2.5D – power-efficient, high bandwidth density
- Dies can be manufactured anywhere and assembled anywhere – can mix 2D and 2.5D in same package – Flexibility for SoC designer



CHARACTERISTICS	STANDARD PACKAGE	ADVANCED PACKAGE
Data Rate (GT/s)	4, 8, 12, 16, 24, 32	
Width (each cluster)	16	64
Bump Pitch (um)	100 – 130	25 - 55
Channel Reach (mm)	<= 25	<=2

KPIs / TARGET FOR KEY METRICS	STANDARD PACKAGE	ADVANCED PACKAGE
B/W Shoreline (GB/s/mm)	28 – 224	165 – 1317
B/W Density (GB/s/mm ²)	22-125	188-1350

UCIe 1.0 spec supports multiple packaging technology options to build an open ecosystem

UCIe-S: Standard Package Bump Maps

- Two options: x16 and x32 bump arrangements for BW/mm flexibility
 - 4-2-4 recommended package stack-up for x16 (two topside stripline routing layers)
 - 8-2-8 recommended package stack-up for x32 (4 topside stripline routing layers) for doubled BW/mm

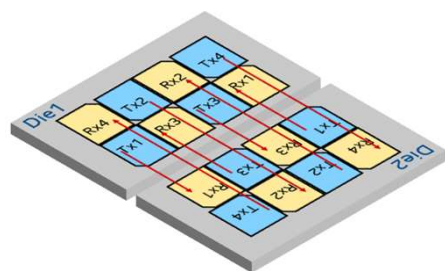
x16 module

x32 module

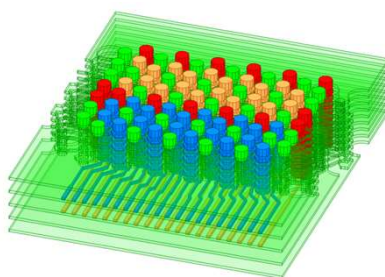
Column 0	Column 1	Column 2	Column 3	Column 4	Column 5	Column 6	Column 7	Column 8	Column 9	Column 10	Column 11
	txdatasb		txcksb		vccaon		vccaon		rxcksb		rxdatasb
vccio		vccio		vccio		vccio		vccio		vccio	
	vss		vss		vss		vss		vss		vss
vccio	txdata5	txdata7	txckn	txdata9		vccio	rxdata10	rxdata8	rxckp	rxdata6	rxdata4
vss		vss		vss		vss		vss		vss	
vss	txdata4		txckp	txdata10		vss	rxdata11	rxckn		rxdata5	rxdata5
	vss	txdata6		txdata8		vss	rxdata9		rxckn	rxdata7	
	vss		vss		vss	vss		vss		vss	
vccio		txdata3		txdata13		vccio	rxdata12		rxdata2		
	txdata1		txvid	txdata15		vccio	rxdata14	rxtrk		rxdata0	
vccio		vss		vss		vccio		vss		vss	
	txdata0		txtrk	txdata14		vss	rxdata15	rxvid		rxdata1	
vss		txdata2		txdata12		vss	rxdata13		rxdata3		
Die Edge											

Column 0	Column 1	Column 2	Column 3	Column 4	Column 5	Column 6	Column 7	Column 8	Column 9	Column 10	Column 11
m1txdatasb	m2rxdatasb		m2rxcksb		vccaon		vccaon		m2txcksb	m1rxcksb	m2txdatasb
	vccio		vccio		vccio		vccio		vccio		vccio
vss		vss		vss		vss		vss		vss	
m2rxdata4	m2rxdata6		m2rxdata8		vss		vss	m2txdata9		m2txdata7	vss
	vss		m2rxckp		m2rxdata10		m2txdata11		m2txckn		m2txdata5
m2rxdata5		m2rxckn		m2rxdata11		m2txdata10		m2txckp		m2txdata4	vss
vss	m2rxdata7		m2rxdata9		vss		vss	m2txdata8		m2txdata6	vss
	vss		vss		vss		vss		vss		vss
m2rxdata0		m2rxtrk		m2rxdata12		vss		m2txdata13		m2txdata3	vss
	vss		vss		vss		vss		vss		vss
m2rxdata1		m2rxvid		m2rxdata15		m2txdata14		m2txtrk		m2txdata0	
vccio	m2rxdata3		m2rxdata13		vccio		vccio	m2txdata12		m2txdata2	vccio
	vss		vss		vccio		vss		vss		vccio
vccio		m1txdata7		m1txdata9		vccio		m1rxdata8		m1rxdata6	
	m1txdata5		m1txckn		m1txdata11		m1rxdata10		m1rxckp		m1rxdata4
vss		vss		vss		vss		vss		vss	
	m1txdata4		m1txckp		m1txdata10		m1rxdata11		m1rxckn		m1rxdata5
vss		m1txdata6		m1txdata8		vss		m1rxdata9		m1rxdata7	
	vss		vss		vss		vss		vss		vss
vccio		m1txdata3		m1txdata13		vccio		m1rxdata12		m1rxdata2	
	m1txdata1		m1txvid		m1txdata15		m1rxdata14		m1rxtrk		m1rxdata0
vccio		vss		vss		vccio		vss		vss	
	m1txdata0		m1txtrk		m1txdata14		m1rxdata15		m1rxvid		m1rxdata1
vss		m1txdata2		m1txdata12		vss		m1rxdata13		m1rxdata3	
Die Edge											

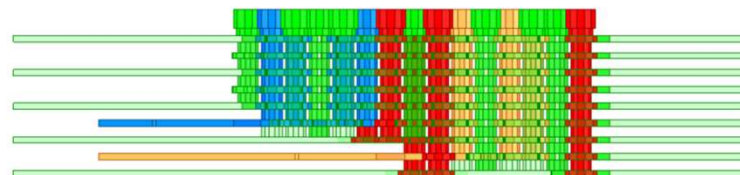
UCIe-S: Arrangement & Channel Characteristics



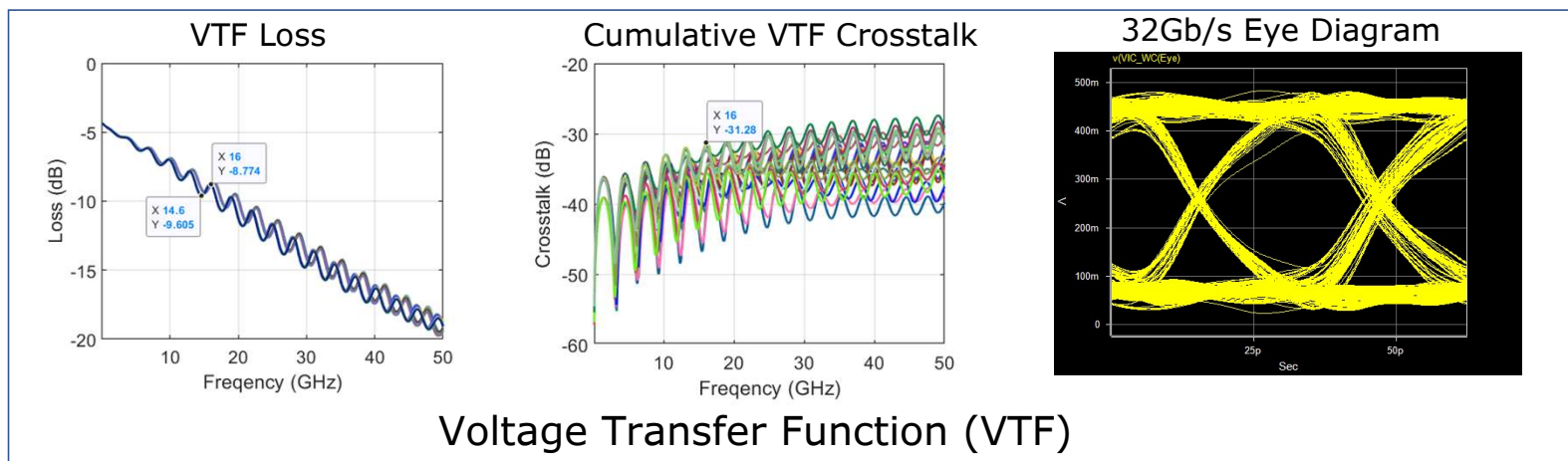
- 2-module stacking



- 18 IO/mm/layer
- 2 routing layers for each module
- 4 routing layers for 2 modules

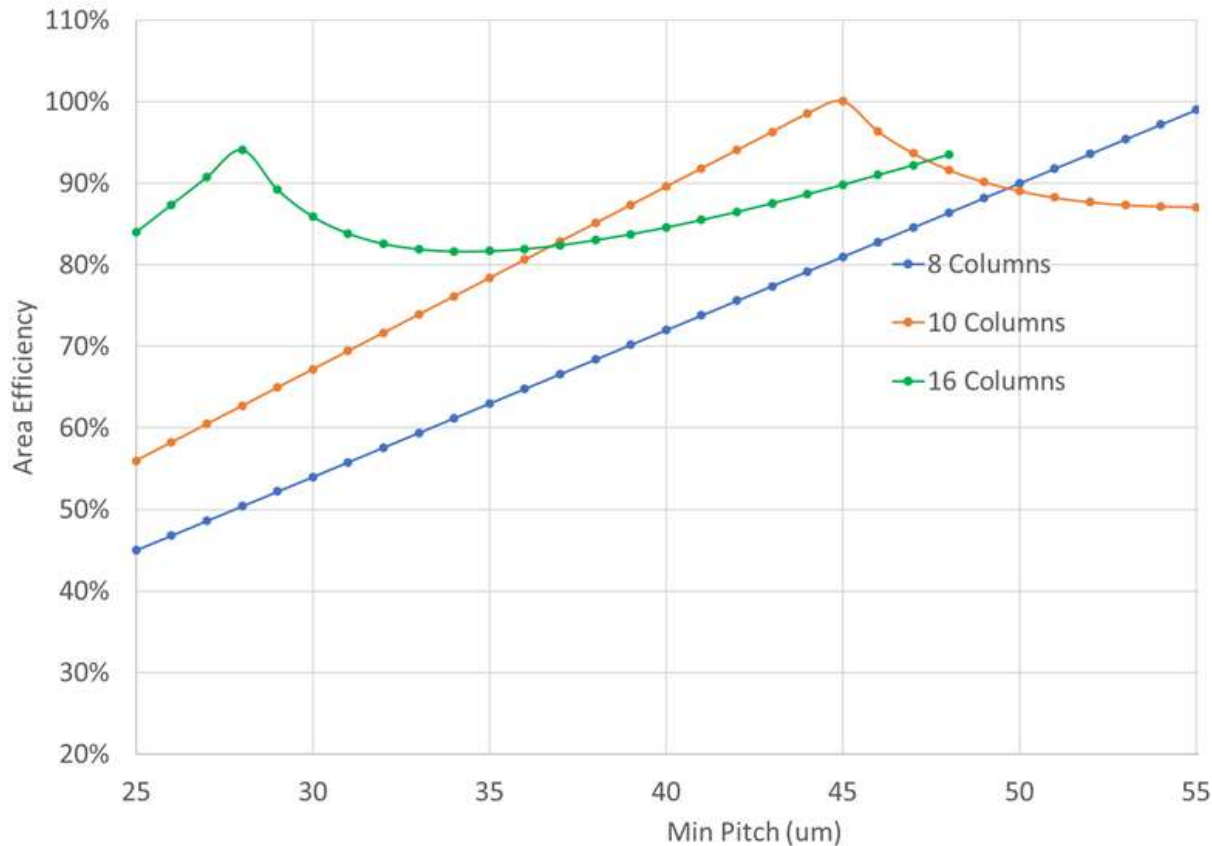


- power
- ground
- signals on L8
- signals on L6
- signals on L4 and L2 not shown



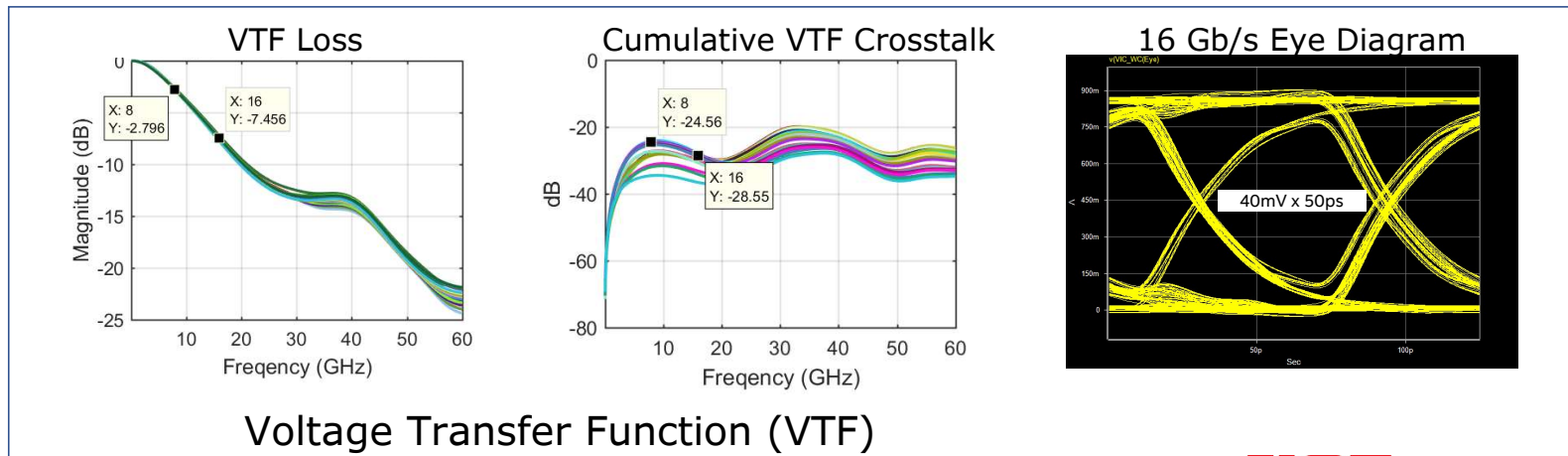
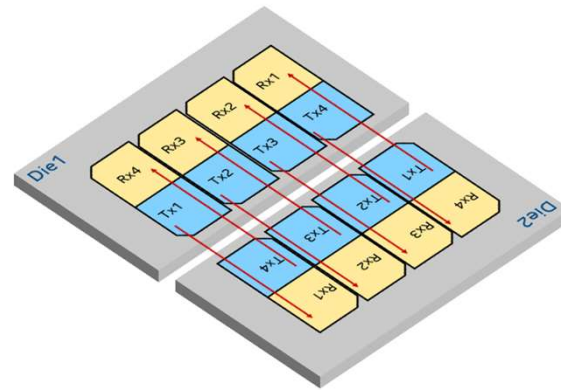
25mm length

UCIe-A area/column type efficiency plots



- Points of overlap are the optimal cross-over points between recommended 8/10/16-column bump maps
- At the lower bump pitch range, >80% area efficiency is acceptable given overall magnitude of PHY depth is lower
- As bump pitch increases, >90% area efficiency is desired due to the much bigger PHY depth (um)
 - Example: 10% of 1000um is greater than 20% of 400um

UCIe-A: Arrangement & Channel Characteristics

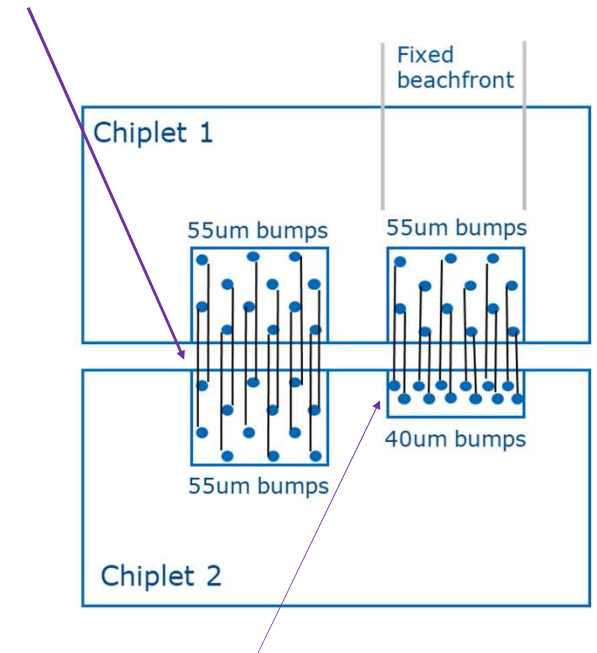


Voltage Transfer Function (VTF)

UCIe-A Interoperability

- Advanced package planning of key parameters up front for interop across IDMs/OSATs:
 - PHY beachfront must be spec to balance BW/mm capability and mechanical compatibility
 - Inter-generational compatibility across bump pitch range
 - Fixed beachfront (388.8um) per PHY module &
 - Signal ordering rules
 - Comprehensive PHY placement & rotation/mirroring rules

CoWos or EMIB or similar tight-pitch tech



- With the reduction of bump pitch, the number of rows decrease while the number of columns increase
- Interop is enabled by a fixed beachfront & following signal ordering rules

UCIe 1.0 delivers the best KPIs while meeting the projected needs for the next 5-6 years across the compute continuum

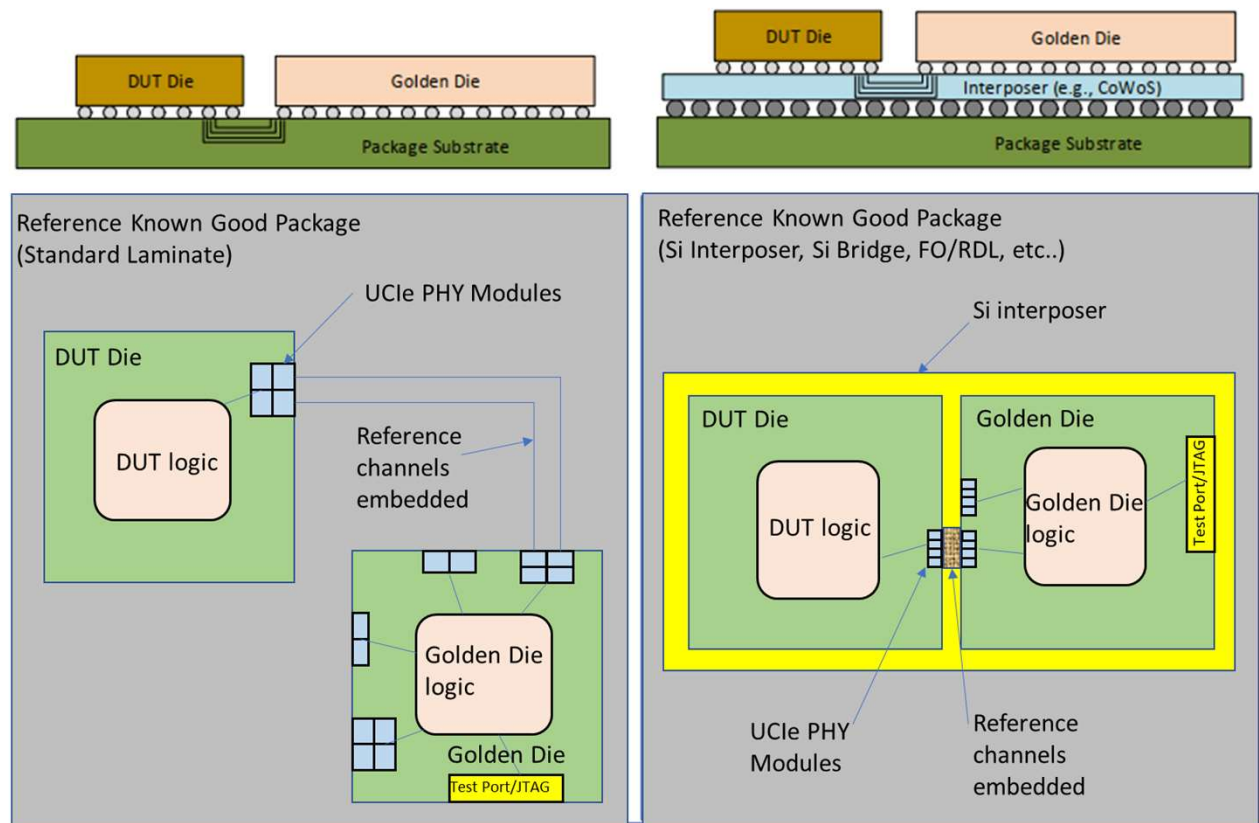
Compliance Overview

- The goal of Compliance testing is to validate the mainband supported features of a Device Under Test (DUT) against a known good reference UCle implementation.
- The UCle sideband link plays a critical role for enabling compliance testing by allowing compliance software to access registers from different UCle components (e.g. Physical Layer, D2D Adapter, etc.) for setting up tests as well as monitoring status.
- Compliance Test Document to describe:
 - Compliance test setup, including the channel model and package level details
 - Test details
 - Golden Die details including form factor and system-level behavior

Compliance Setup

Consist of:

- Reference UCle implementation across all layers of the UCle stack (Golden UCle)
- DUT: to be tested with reference design
 - Required to have cleared die sort/pre-bond testing
- For Advanced Package, a known good silicon bridge or interposer.



Protocol and Adapter Compliance

- Protocol Layer Compliance
 - For PCIe and CXL Protocol Layers, UCle leverage the protocol compliance defined in those specs.
 - For Streaming protocols, Protocol interop is specific to the protocol being streamed, beyond scope of UCle spec.
- Adapter Compliance:
 - Golden Die Adapter must have all the capabilities defined in UCle spec, and must have the capability to inject both consistent and inconsistent sideband messages to test DUT for various error scenarios.
 - DUT must have Control and Status registers for
 - Ability to Inject Test or NOP Flits
 - Injection of Link State Request or Response sideband messages
 - Retry injection control

PHY Compliance

- Golden Die must support capabilities to force timeouts on all applicable sideband messages as well as state residence timers.
- Electrical Compliance Features:
 - Timing margining
 - Voltage margining, when supported
 - BER measurement
 - Lane-to-Lane skew for a given module at both RX and TX
 - TX Equalization